GP1S092HCPIF

SMT, Gap: 2mm, Slit: 0.3mm Phototransistor Output, **Compact Transmissive Photointerrupter**



Description

GP1S092HCPIF is a compact-package, phototransistor output, transmissive photointerrupter, with opposing emitter and detector in a molding that provides non-contact sensing. The compact package series is a result of unique technology combing transfer and injection molding.

This surface mount device has a shaped positioning pin to assure accurate PCB placement, of the emitter and detector. It is unique, because it is one of the few photointerrupters that comes in Tape and Reel packaging, for use with highly automated pick and place equipment.

Features

- 1. Transmissive with phototransistor output
- 2. Highlights:
 - · Compact Size
 - · Positioning Pin "D" shaped to prevent misalignment
 - Surface Mount Type (SMT)
 - Tape and Reel (T&R) 2 000 pcs per reel
- 3. Key Parameters:
 - Gap Width : 2mm
 - Slit Width (detector side): 0.3mm
 - Package : 4.5×2.6×2.9 mm
- 4. Lead free and RoHS directive compliant

Agency approvals/Compliance

1. Compliant with RoHS directive

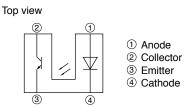
Applications

- 1. General purpose detection of object presence or motion.
- 2. Example: printer, lens control for camera

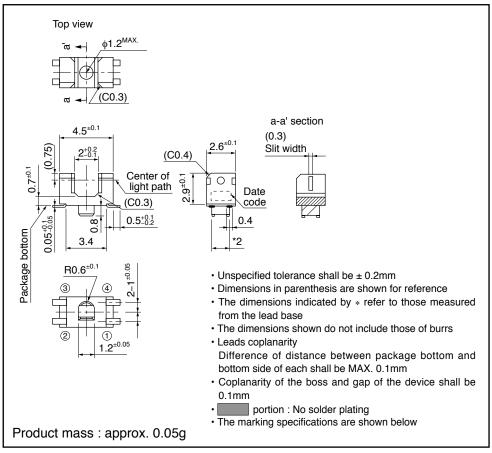
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Internal Connection Diagram



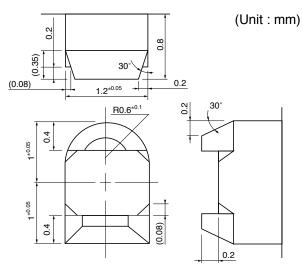
Outline Dimensions



Plating material : SnCu (Cu : TYP. 2%)

(Unit : mm)

Details of positioning pin dimensions



Date code (2 digit)

	-7		
digit	2nd digit		
Year of production		production	
Mark	Month	Mark	
0	1	1	
1	2	2	
2	3	3	
3	4	4	
4	5	5	
5	6	6	
6	7	7	
7	8	8	
8	9	9	
9	10	X	
0	11	Y	
•	12	Z	
	roduction Mark 0 1 2 3 4 5 6 7 8 9	roduction Month of p Mark Month 0 1 1 2 2 3 3 4 4 5 5 6 6 7 7 8 8 9 9 10 0 11	

repeats in a 10 year cycle

Rank mark

There is no rank indicator.

Country of origin Japan

Absolute Maximum Ratings

Absolute Maximum Ratings					
	Parameter	Symbol	Rating	Unit	
	Forward current	$I_{\rm F}$	50	mA	
Input	Reverse voltage	V _R	6	V	
	Power dissipation	Р	75	mW	
	Collector-emitter voltage	V _{CEO}	35	V	
Output	Emitter-collector voltage	V _{ECO}	6	V	
Output	Collector current	I _C	20	mA	
	Collector power dissipation	P _C	75	mW	
Total power dissipation		P _{tot}	100	mW	
Operating temperature		T _{opr}	-25 to +85	°C	
Storage temperature		T _{stg}	-40 to +100	°C	
*1Soldering temperature		T _{sol}	260	°C	

*1 For 5s or less

■ Electro-optical Characteristics

 $(T_a=25^{\circ}C)$

							($r_a = 20 (0)$
	Parameter		Symbol	Condition	MIN.	TYP.	MAX.	Unit
Innut	Forward voltage		$V_{\rm F}$	I _F =20mA	-	1.2	1.4	V
Input	Reverse current		I _R	V _R =3V	_	_	10	μΑ
Output	t Collector dark current		I _{CEO}	$V_{CE}=20V$	-	_	100	nA
Transfer	for Collector current		I _C	V_{CE} =5V, I_{F} =5mA	100	_	400	μA
charac-	Collector-emitter saturation voltage		V _{CE(sat)}	$I_F=10mA$, $I_C=40\mu A$	_	_	0.4	V
teristics Response time	Rise time	t _r	V_{CE} =5V, I_{C} =100 μ A, R_{L} =1 $k\Omega$	_	50	150	μs	
	Fall time	t _f		-	50	150	μs	





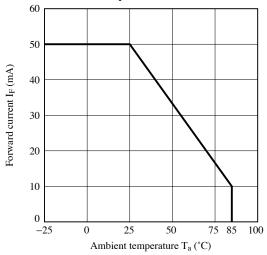


Fig.3 Forward Current vs. Forward Voltage

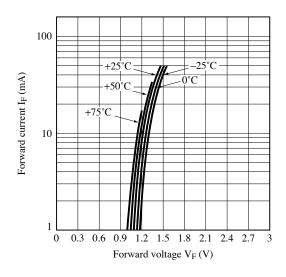


Fig.5 Collector Current vs. Collector-emitter Voltage

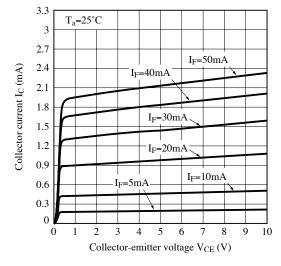


Fig.2 Power Dissipation vs. Ambient Temperature

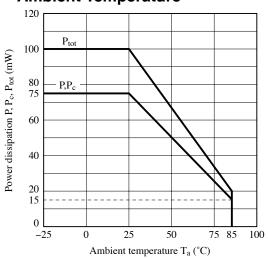


Fig.4 Collector Current vs. Forward Current

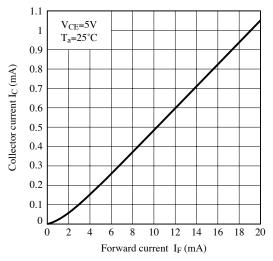


Fig.6 Relative Collector Current vs. Ambient Temperature

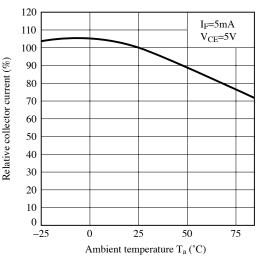




Fig.7 Collector-emitter Saturation Voltage vs. Ambient Temperature

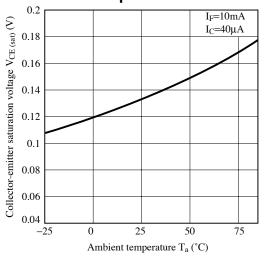


Fig.9 Response Time vs. Load Resistance

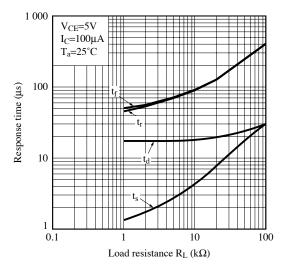


Fig.11 Detecting Position Characteristics (1)

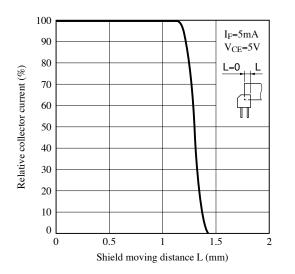


Fig.8 Collector Dark Current vs. Ambient Temperature

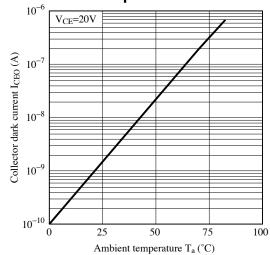
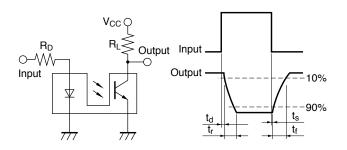
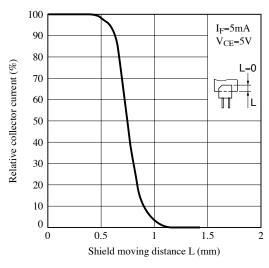
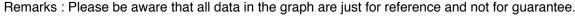


Fig.10 Test Circuit for Response Time











Design Considerations

Design guide

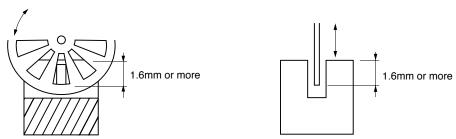
1) Prevention of detection error

To prevent photointerrupter from faulty operation caused by external light, do not set the detecting face to the external light.

2) Position of opaque board

Opaque board shall be installed at place 1.6mm or more from the top of elements.





This product is not designed against irradiation and incorporates non-coherent IRED.

Degradation

In general, the emission of the IRED used in photointerrupter will degrade over time.

In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

Used parts

This product is assembled using the below parts.

• Photodetector (qty. : 1)

Category	Material Maximum Sensitivity wavelength (nm)		Sensitivity wavelength (nm)	Response time (µs)
Phototransistor	Silicon (Si)	930	700 to 1 200	20

• Photo emitter (qty. : 1)

Category Material		Maximum light emitting wavelength (nm)	I/O Frequency (MHz)	
Infrared emitting diode (non-coherent)	Gallium arsenide (GaAs)	950	0.3	

Material

Case	Lead frame	Lead frame plating
Black polyphernylene sulfide resin (UL94 V-0)	42Alloy	SnCu plating

Manufacturing Guidelines

• Storage and management after open

Storage condition

Storage temp.: 5 to 30 $^{\circ}\text{C},$ Storage humidity : 70%RH or less at regular packaging.

Treatment after opening the moisture-proof package

After opening, you should mount the products while keeping them on the condition of 5 to 25°C and 70%RH or less in humidity within 4 days.

After opening the bag once even if the prolonged storage is necessary, you should mount the products within two weeks.

And when you store the rest of products you should put into a DRY BOX. Otherwise after the rest of products and silicagel are sealed up again, you should keep them under the condition of 5 to 30°C and 70%RH or less in humidity.

Baking before mounting

When the above-mentioned storage method could not be executed, please process the baking treatment before mounting the products.

However the baking treatment is permitted within one time.

Recommended condition : 125°C, 16 to 24 hours

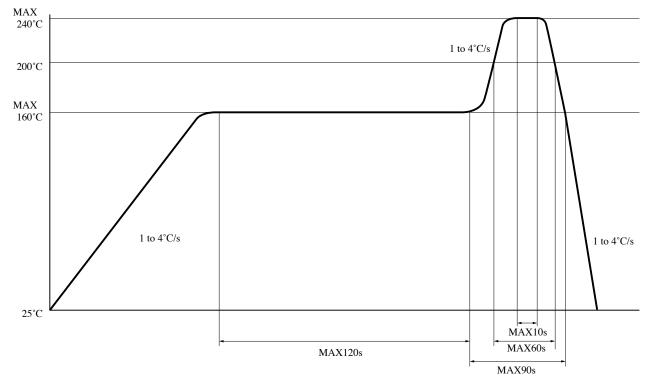
*Do not process the baking treatment with the product wrapped. When the baking treatment processing, you should move the products to a metallic tray or fix temporarily the products to substrate.



• Soldering Method

Reflow Soldering:

Reflow soldering should follow the temperature profile shown below. Soldering should not exceed the curve of temperature profile and time. Please solder within one time.



Hand soldering

Hand soldering should be completed within 3 s when the point of solder iron is below 350°C. Please solder within one time.

Please don't touch the terminals directly by soldering iron.

Soldered product shall treat at normal temperature.

Other notice

Please take care not to let any external force exert on lead pins.

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the cooling and soldering conditions.

Lead terminals

Lead terminals of this product are tin copper alloy plated. Before usage, please evaluate solderability with actual conditions and confirm. And the uniformity in color for the lead terminals are not specified.



• Cleaning instructions

Solvent cleaning :

Solvent temperature should be 45°C or below. Immersion time should be 3 minutes or less.

Ultrasonic cleaning :

Do not execute ultrasonic cleaning.

Recommended solvent materials :

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol.

• Presence of ODC

This product shall not contain the following materials. And they are not used in the production process for this product. Regulation substances : CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBBOs and PBBs are not used in this product at all.

This product shall not contain the following materials banned in the RoHS Directive (2002/95/EC). •Lead, Mercury, Cadmium, Hexavalent chromium, Polybrominated biphenyls (PBB), Polybrominated diphenyl ethers (PBDE).



Package specification

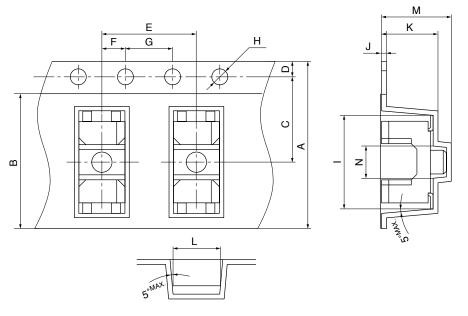
Package materials

Carrier tape : PS (with anti-static material) Cover tape : PET (three layer system) Reel : PS

Package method

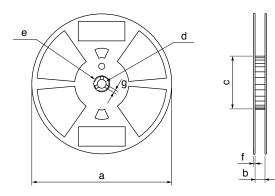
2 000 pcs of products shall be packaged in a reel. One reed with silicagel is endased in aluminum laminated bag. After sealing up the bag, it encased in one case (5 bags/case).

Carrier tape structure and Dimensions



Dimensions List (Unit : mm)						nit : mm)
А	В	С	D	Е	F	G
12 ^{±0.3}	$9.5^{+0.3}_{-0.2}$	$5.5^{\pm 0.05}$	$1.75^{\pm 0.1}$	8 ^{±0.1}	$2^{\pm 0.05}$	$4^{\pm 0.1}$
Н	Ι	J	K	L	М	N
φ1.5 ^{+0.1}	$6.1^{\pm 0.1}$	$0.4^{\pm 0.05}$	$3.2^{\pm 0.1}$	2.8 ^{±0.1}	$4.3^{\pm 0.1}$	$1.45^{\pm 0.1}$

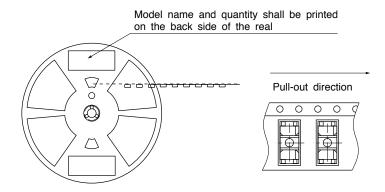
Reel structure and Dimensions



Dimensio	ns List	(Unit : mm)		
а	b	с	d	
330 ^{±1}	13 ^{±1}	80 ^{±1}	13 ^{±0.5}	
e	f	g		
21 ^{±1}	2 ^{±0.5}	2 ^{±0.5}		



Direction of product insertion



[Packing : 2 000pcs/reel]

Storage method

Storage conditions should follow the condition shown below.

Storage temperature : 5 to 30 $^\circ\text{C}$

Storage hunidity : 70%RH or less

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- --- Personal computers
- --- Office automation equipment
- --- Telecommunication equipment [terminal]
- --- Test and measurement equipment
- --- Industrial control
- --- Audio visual equipment
- --- Consumer electronics

(ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection with equipment that requires higher reliability such as:

- --- Transportation control and safety equipment (i.e., aircraft, trains, automobiles, etc.)
- --- Traffic signals
- --- Gas leakage sensor breakers
- --- Alarm equipment
- --- Various safety devices, etc.

(iii) SHARP devices shall not be used for or in connection with equipment that requires an extremely high level of reliability and safety such as:

- --- Space applications
- --- Telecommunication equipment [trunk lines]
- --- Nuclear power control equipment
- --- Medical and other life support equipment (e.g., scuba).

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